Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination BAEK ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,445,437	09-2002	Miyazaki et al.	349/156
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*	,	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	404134401	05-1992	Japan	Kobayashi et al.	G02B 005/20
	0					
	Р					
	Q					
	R					
	s					
	T				\$	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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	w						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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